Searcn Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/766,817	SHINO ET AL.	
Examiner	Art Unit	
David Vu	2828	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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345	76		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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